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10771553_CLS Most Frequently Occurring Classifications of Patents Returned From A Search of 10814207 on May 27, 2004

| Origin 17 | nal Classifications 250/288 204/452 210/198.2 204/453 216/2 250/281 204/451 204/603 210/656 216/79 |
|--------------------------------------|--|
| 20 14 14 10 9 | S-Reference Classifications 250/288 250/281 250/282 210/748 210/243 204/603 |
| 7 7 | 204/600 204/601 210/198.2 210/656 |
| 7 7 5 5 4 | 250/423R 438/743 204/452 |
| 4 4 3 3 | 204/604 438/723 216/67 216/79 |
| 3 3 3 3 3 3 | 250/292 436/161 438/734 |
| | 438/736 438/942 204/450 204/451 |
| 2 2 2 2 2 2 2 2 | 216/39 216/47 216/80 |
| 2 2 2 | 422/70 436/173 436/174 |

2 436/177

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- 2 436/86
- 2 436/87
- 2 436/89
- 2 436/91
- 2 436/93
- 2 436/94
- 2 438/756

Combined Classifications

- 37 250/288
- 250/281 17
- 14 250/282
- 12 210/198.2
- 10 204/603
- 10 210/748
- 9 204/452
- 210/243
- 9 210/656 8 204/601
- 7 204/600
- 5 216/79
- 5 250/423R
- 5 438/743
- 4 204/451
- 4 204/453
- 4 204/604
- 438/723
- 3 216/2
- 3 216/67
- 3 250/292
- 3 436/161
- 3 436/173
- 3 438/734
- 3 438/736
- 3 438/942
- 2 204/450
- 2 216/39
- 2 216/47
- 2 216/80
- 2 250/289
- 2 422/70
- 2 436/174
- 2 436/177
- 2 436/86
- 2 436/87
- 2 436/89
- 2 436/91
- 436/93

2 436/94 2 438/756

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10771553 CLSTITLES

Titles of Most Frequently Occurring Classifications of Patents Returne

From A Search of 10814207 on May 27, 2004

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(17 OR, 20 XR)
 37
    250/288
          Class
                  250 : RADIANT ENERGY
                        IONIC SEPARATION OR ANALYSIS
          250/281
          250/288
                        .With sample supply means
                   (3 OR, 14 XR)
 17
    250/281
          Class
                  250 : RADIANT ENERGY
                        IONIC SEPARATION OR ANALYSIS
          250/281
 14 250/282
                   (0 OR, 14 XR)
                  250 : RADIANT ENERGY
          Class
          250/281
                        IONIC SEPARATION OR ANALYSIS
          250/282
                        .Methods
 12 210/198.2
                   (5 OR, 7 XR)
                  210 : LIQUID PURIFICATION OR SEPARATION
                        WITH MEANS TO ADD TREATING MATERIAL
          210/198.1
          210/198.2
                        .Chromatography
 10 204/603
                   (2 OR, 8 XR)
                  204 : CHEMISTRY: ELECTRICAL AND WAVE ENERGY
          Class
          204/193
                        APPARATUS
          204/600
                        .Electrophoretic or electro-osmotic apparatus
          204/601
                        .. Capillary electrophoresis type
          204/603
                        ...With detailed detection system (e.g.,
                           including a light source and a camera, etc.
 10 210/748
                   (0 OR, 10 XR)
                  210 : LIOUID PURIFICATION OR SEPARATION
          Class
          210/600
                        PROCESSES
          210/748
                        .Utilizing electrical or wave energy (directly
                           applied to liquid or material being treated
    204/452
                   (5 OR, 4 XR)
          Class
                  204 : CHEMISTRY: ELECTRICAL AND WAVE ENERGY
                        .Electrophoresis or electro-osmosis processes
          204/450
                             and electrolyte compositions therefor whe
n not provided for
                             elsewhere
          204/451
                        .. Capillary electrophoresis
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...With detailed detection

9 210/243 (0 OR, 9 XR)

> Class 210 : LIOUID PURIFICATION OR SEPARATION ELECTRICAL INSULATING OR ELECTRICITY 210/243 DISCHARGING

9 210/656 (2 OR, 7 XR)

Class 210 : LIQUID PURIFICATION OR SEPARATION

210/600 PROCESSES

210/656 .Chromatography

(1 OR, 7 XR) 8 204/601

Class 204: CHEMISTRY: ELECTRICAL AND WAVE ENERGY

204/193 APPARATUS

204/600 .Electrophoretic or electro-osmotic apparatus

204/601 .. Capillary electrophoresis type

7 204/600 (0 OR, 7 XR)

Class 204: CHEMISTRY: ELECTRICAL AND WAVE ENERGY

204/193

APPARATUS
.Electrophoretic or electro-osmotic apparatus 204/600

5 216/79 (2 OR, 3 XR)

Class 216: ETCHING A SUBSTRATE: PROCESSES

216/58 GAS PHASE ETCHING OF SUBSTRATE

216/74 .Etching inorganic substrate

216/79 .. Etching silicon containing substrate

250/423R (0 OR, 5 XR)

Class 250: RADIANT ENERGY

250/423R ION GENERATION

(0 OR, 5 XR) 5 438/743

Class 438: SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS

438/689 CHEMICAL ETCHING

.Vapor phase etching (i.e., dry etching) 438/706

..Differential etching of semiconductor 438/735

substrate

438/737 ... Substrate possessing multiple layers

438/743Silicon oxide or glass

(2 OR, 2 XR) 4 204/451

Class 204: CHEMISTRY: ELECTRICAL AND WAVE ENERGY

204/450 .Electrophoresis or electro-osmosis processes

10771553 CLSTITLES and electrolyte compositions therefor when not provided for elsewhere 204/451 .. Capillary electrophoresis (3 OR, 1 XR) 204/453 204 : CHEMISTRY: ELECTRICAL AND WAVE ENERGY 204/450 .Electrophoresis or electro-osmosis processes and electrolyte compositions therefor whe n not provided for elsewhere 204/451 .. Capillary electrophoresis 204/453 ...With injection 204/604 (0 OR, 4 XR) 204 : CHEMISTRY: ELECTRICAL AND WAVE ENERGY Class 204/193 APPARATUS 204/600 .Electrophoretic or electro-osmotic apparatus 204/601 .. Capillary electrophoresis type 204/604 ...With injector 438/723 (0 OR, 4 XR)438 : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS Class 438/689 CHEMICAL ETCHING 438/706 .Vapor phase etching (i.e., dry etching) .. Utilizing electromagnetic or wave energy 438/707 438/710 ... By creating electric field (e.g., plasma, glow discharge, etc.)Silicon oxide or glass 438/723 3 216/2 (3 OR, 0 XR) 216 : ETCHING A SUBSTRATE: PROCESSES Class ETCHING OF SEMICONDUCTOR MATERIAL TO PRODUCE A 216/2 Ν ARTICLE HAVING A NONELECTRICAL FUNCTION 216/67 (0 OR, 3 XR) 216 : ETCHING A SUBSTRATE: PROCESSES Class GAS PHASE ETCHING OF SUBSTRATE 216/58 216/63 .Application of energy to the gaseous etchant or to the substrate being etched 216/67 .. Using plasma 250/292 (0 OR, 3 XR)

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IONIC SEPARATION OR ANALYSIS

250 : RADIANT ENERGY

Class

250/281

| | 250/290 | 10771553_CLSTITLES .Cyclically varying ion selecting field means |
|------|-------------------------------|--|
| | 250/292 | Laterally resonant ion path |
| 3 | 436/161 Class | OR, 3 XR) : CHEMISTRY: ANALYTICAL AND IMMUNOLOGICAL TESTING |
| | 436/161 | |
| 3 | 100, 1.0 | OR, 2 XR) : CHEMISTRY: ANALYTICAL AND IMMUNOLOGICAL TESTING |
| | 436/173 | NUCLEAR MAGNETIC RESONANCE, ELECTRON SPIN RESONANCE OR OTHER SPIN EFFECTS OR MASS SPE |
| CTRO | DMETRY | RESOLUTION ON STILL STILL ON THIS STE |
| 3 | 438/734 Class | OR, 3 XR) : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS |
| | 438/689 438/706 438/734 | |
| 3 | | OR, 3 XR) : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS |
| | 438/689 438/706 438/735 | CHEMICAL ETCHING .Vapor phase etching (i.e., dry etching)Differential etching of semiconductor substrate |
| | 438/736 | |
| 3 | 438/942 Class | OR, 3 XR) : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS |
| | 438/942 | MASKING |
| 2 | 204/450 Class 204/450 | OR, 2 XR) : CHEMISTRY: ELECTRICAL AND WAVE ENERGY .Electrophoresis or electro-osmosis processes and electrolyte compositions therefor when |
| not | provided for | elsewhere |
| | | |
| 2 | 216/39 Class 216/39 | OR, 2 XR) : ETCHING A SUBSTRATE: PROCESSES FORMING GROOVE OR HOLE IN A SUBSTRATE WHICH IS SUBSEQUENTLY FILLED OR COATED |

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| Т | 2 | 216/47 Class 216/41 | 216 | : ETCHING A SUBSTRATE: PROCESSES |
|---|---|--|------------------------|--|
| | | 216/47 | | TO AN ETCHANT (I.E., ETCH RESIST) .Mask is multilayer resist |
| | 2 | 216/80 Class 216/58 216/74 216/79 216/80 | 216 | OR, 2 XR) : ETCHING A SUBSTRATE: PROCESSES GAS PHASE ETCHING OF SUBSTRATE .Etching inorganic substrate .Etching silicon containing substrateSilicon containing substrate is glass |
| | 2 | 250/289 Class 250/281 250/289 | 250 | : RADIANT ENERGY IONIC SEPARATION OR ANALYSIS |
| | 2 | 422/70 Class 422/50 | | OR, 2 XR) : CHEMICAL APPARATUS AND PROCESS DISINFECTING, DEODORIZING, PRESERVING, OR STERILIZING ANALYZER, STRUCTURED INDICATOR, OR MANIPULATIV |
| Ε | | 422/68.3 | | |
| | | 422/69 422/70 | | Sorption testingLiquid chromatography |
| | 2 | 422/70 436/174 Class | (0 436 | Liquid chromatography |
| | | 422/70 436/174 Class 436/174 436/177 | (0 436 (0 436 | Liquid chromatography OR, 2 XR) : CHEMISTRY: ANALYTICAL AND IMMUNOLOGICAL TESTING INCLUDING SAMPLE PREPARATION OR, 2 XR) : CHEMISTRY: ANALYTICAL AND IMMUNOLOGICAL TESTING INCLUDING SAMPLE PREPARATION .Liberation or purification of sample or |
| f | 2 | 422/70 436/174 Class 436/174 436/177 Class 436/174 | (0 436 (0 436 | Liquid chromatography OR, 2 XR) : CHEMISTRY: ANALYTICAL AND IMMUNOLOGICAL TESTING INCLUDING SAMPLE PREPARATION OR, 2 XR) : CHEMISTRY: ANALYTICAL AND IMMUNOLOGICAL TESTING INCLUDING SAMPLE PREPARATION |

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| 2 | | (0 OR, 2 XR) 436: CHEMISTRY: ANALYTICAL AND IMMUNOLOGICAL TESTING PEPTIDE, PROTEIN OR AMINO ACID .Glycoproteins (e.g., hormone, etc.) | |
|---|-------------------------------------|---|----|
| 2 | 436/89 Class 436/86 436/89 | 436: CHEMISTRY: ANALYTICAL AND IMMUNOLOGICAL TESTING PEPTIDE, PROTEIN OR AMINO ACID | |
| 2 | | (0 OR, 2 XR) 436: CHEMISTRY: ANALYTICAL AND IMMUNOLOGICAL TESTING HETEROCYCLIC CARBON COMPOUND (I.E., 0, S, N Se, Te, AS ONLY RING HETERO ATOM) | ., |
| 2 | 436/93 Class 436/91 436/93 | (0 OR, 2 XR) 436: CHEMISTRY: ANALYTICAL AND IMMUNOLOGICAL TESTING HETEROCYCLIC CARBON COMPOUND (I.E., 0, S, N Se, Te, AS ONLY RING HETERO ATOM) .Hetero-O (e.g., ascorbic acid, etc.) | ., |
| 2 | 436/91 436/93 | 436 : CHEMISTRY: ANALYTICAL AND IMMUNOLOGICAL TESTING | , |
| 2 | | (0 OR, 2 XR) 438: SEMICONDUCTOR DEVICE MANUFACTURING: PROCES CHEMICAL ETCHING .Liquid phase etching Silicon oxide | S |